



FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT

ATTY DOCKET NO.

55338(70868)

SERIAL NO.

09/720,475

APPLICANT(S): Kazuyuki NAKO, et al.

FILING DATE:

December 22, 2000

ART UNIT:

Not Assigned

UNITED STATES PATENT DOCUMENTS

EXAM. INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FIL. DATE IF APPR
JHE	A1	5,973,802	October 26, 1999	Hirota, et al.	358	521	
JHE	A2	5,760,930	June 2, 1998	Fukuzawa, et al.	358	521	
JHE	A3	5,687,006	November 11, 1997	Namizuka, et al.	358	462	

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRAN YES/NO
JHE	B1	JP 4365182	December 17, 1992	JAPAN	—	—	
JHE	B2	JP 6014185	January 21, 1994	JAPAN	—	—	
JHE	B3	JP 6-62216	March 4, 1994	JAPAN	—	—	
JHE	B4	JP 8-340447	December 24, 1996	JAPAN	—	—	
JHE	B5	JP 4-219882	August 10, 1992	JAPAN	—	—	
					—	—	

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

JHE	C1	Hitoshi Kiya, "Resolution Conversion of Digital Image", CQ Publishing, The Interface, June 1998; Japan, pp. 72-80.
Examiner:	Jen Cato	Date: 2/22/05



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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRAN YES/NO
C							
YAL	B6	JP 8-251427	September 27, 1996	JAPAN	—	—	Abstract
YAL	B7	JP 62-180688	August 7, 1987	JAPAN	—	—	Abstract
YAL	B8	JP 5-336386	December 17, 1993	JAPAN	—	—	Abstract
YAL	B9	JP 5-258035	October 8, 1993	JAPAN	—	—	Abstract
YAL	B10	JP 8-18778	January 19, 1996	JAPAN	—	—	Abstract
YAL	B11	JP 63-244973	October 12, 1988	JAPAN	—	—	Abstract
YAL	B12	3-82269	April 8, 1991	JAPAN	—	—	Abstract
YAL	B13	3-85061	April 10, 1991	JAPAN	—	—	Abstract
YAL	B14	8-265563	October 11, 1996	JAPAN	—	—	Abstract
YAL	B15	9-233319	September 5, 1997	JAPAN	—	—	Abstract
YAL	B16	9-312770	December 2, 1997	JAPAN	—	—	Abstract
YAL	B17	61-276077	December 6, 1986	JAPAN	—	—	Abstract

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

Examiner:

Lee Cook

Date:

2/22/01

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55338 (70868)Serial No.
09/720,475**RECEIVED**

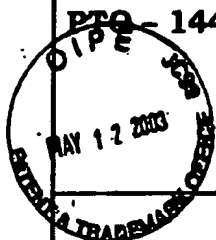
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Applicant(s): Nako, et al.

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December 22, 2000Art Unit
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PTO - 1449

**UNITED STATES PATENT DOCUMENTS**

Exam. Initials	Ref. No.	Document Number	Date	Name	Class	File Date

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Exam. Initials	Ref. No.	Document Number	Date	Country or Office	Class	
<i>SW</i>	B1	57178474	02/11/1982	Japan	—	—

OTHER DOCUMENTS (INCL. TITLE, AUTHOR, DATE, PAGES, ETC)

Exam. Initials	Ref. No.	

Examiner:

SW Cab

Date:

2/22/05

**Information Disclosure
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Applicant(s): Nako, et al.

Filing Date
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UNITED STATES PATENT DOCUMENTS

Exam. Initials	Ref. No.	Document Number	Date	Name	Class	File Date
<i>SAE</i>	A1	5,953,463	9/14/1999	Tanaka et al.	382/298	
<i>SAE</i>	A2	5,832,141	11/3/1998	Ishida et al.	382/296	

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Exam. Initials	Ref. No.	Document Number	Date	Country or Office	Class	
<i>SAE</i>	B1	JP-A 9-200504	7/31/1997	Japan	—	—
<i>SAE</i>	B2	JP-A 6-334856	12/02/1994	Japan	—	—
<i>SAE</i>	B3	JP-A 5-022572	01/29/1993	Japan	—	—
<i>SAE</i>	B4	JP-A 7-087295	03/31/1995	Japan	—	—
<i>SAE</i>	B5	JP-A 7-121692	05/12/1995	Japan	—	—

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Statement****PTO - 1449**Atty. Docket No
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Exam. Initials	Ref. No.	Document Number	Date	Name	Class	File Date
JAC	A1	6,504,628	01/7/2003	Kanno et al.	358/522	

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Exam. Initials	Ref. No.	Document Number	Date	Country or Office	Class	
JAC	B1	CN 1201169	12/09/1998	China	—	—

OTHER DOCUMENTS (INCL. TITLE, AUTHOR, DATE, PAGES, ETC)


Exam. Initials	Ref. No.	

Examiner:

John Cant

Date:

01/22/03

Information Disclosure Statement PTO - 1449		Atty. Docket No 55338 (70868)		Serial No. 09/720,475		
		Applicant(s): Nako, et al.				
		Filing Date December 22, 2000		Art Unit Not Yet Assigned		
UNITED STATES PATENT DOCUMENTS						
Exam. Initials	Ref. No.	Document Number	Date	Name	Class	File Date
Jhe	A1	5,666,208	09/9/1997	Farrell et al.	358/296	
Jhe	A2	5,841,148	11/24/1998	Some et al.	250/684	
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Exam. Initials	Ref. No.	Document Number	Date	Country or Office	Class	
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Jhe	B2	JP-A 9-233313	09/5/1997	Japan	—	—
Jhe	B3	JP-A 8-82880	03/26/1996	Japan	—	—
Jhe	B4	JP-A 9-330393	12/22/1997	Japan	—	—
Jhe	B5	JP-A 9-35063	02/7/1997	Japan	—	—
Jhe	B6	JP-A 7-15657	01/17/1995	Japan	—	—
OTHER DOCUMENTS (INCL. TITLE, AUTHOR, DATE, PAGES, ETC)						
Exam. Initials	Ref. No.					
Examiner: <i>Jhe Cab</i>		Date: <i>01/21/03</i>				



PTO/SB/02a/b (08-03)
Approved for use through 07/31/2008. OMB 0651-0031
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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete if Known			
		Application Number	09/720,475-Conf. #2443		
		Filing Date	March 8, 2001		
		First Named Inventor	Kazuyuki Nakamura		
		Art Unit	2626		
		Examiner Name	M. A. V. Nguyen		
Sheet	1	of	1	Attorney Docket Number	55338(70868)

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U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
JA	AA	US-5,452,374	09-19-1995	Cullen et al.	322 / 293

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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Country Code ³ -Number-Kind Code ² (if known)				
JA	BA	EP-0 785 529 A1	07-23-1997	—	—	
JA	BB	EP-0 650 287 A2	04-26-1995	—	—	
JA	BC	EP-0 784 396 A2	07-16-1997	—	—	
JA	BD	EP-0 432 723 A2	06-19-1991	—	—	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 601.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁴
JA	CA	Jiang H-F et al.: "A fast approach to the detection and correction of skew documents," Pattern Recognition Letters, Vol. 18, No. 7, July 1997, pp. 675-686.	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	<i>Jan C. [Signature]</i>	Date Considered	2/21/05
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